

PATENT APPLICATION B LANGUA EMARK OFFICE

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N THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Minoru KATAYAMA et al.

Group Art Unit: 2856

Application No.: 09/690,590

Examiner:

M. Cygan

HNOLOGY CENTER 2800

Filed: October 18, 2000

Docket No.:

107612

For:

SURFACE TEXTURE MEASURING MACHINE, LEVELING DEVICE FOR

SURFACE TEXTURE MEASURING MACHINE AND ORIENTATION-ADJUSTING

METHOD OF WORKPIECE OF SURFACE TEXTURE MEASURING MACHINE

SUPPLEMENTAL AMENDMENT

Director of the U.S. Patent and Trademark Office Washington, D.C. 20231

Sir:

Further to the amendment filed on March 12, 2002 and the March 26, 2002 personal interview, please amend the above-identified application as follows:

IN THE CLAIMS:

Please replace claims 1, 2, 4 and 6-8 as follows:

Syx

1. (Amended) A surface texture measuring machine for measuring a surface texture of a workpiece held on a workpiece orientation adjustment stage, the workpiece having an edge line, the workpiece orientation adjustment stage being movable in a measurement direction (X-axis direction) and in a direction (Y-axis direction) orthogonal with the X-axis direction within a horizontal plane and rotatable in a X-Y plane, the workpiece orientation adjustment stage being capable of seesawing in a direction (Z-axis direction) orthogonal with the X-axis direction within a perpendicular plane, and the surface texture of the workpiece being scanned by a sensor movable in the X-axis direction after adjusting orientation of the workpiece orientation adjustment stage, the surface texture measuring machine comprising: